


<b>Search Notes</b>  	<b>Application/Control No.</b>  10561395	<b>Applicant(s)/Patent Under Reexamination</b>  MEIER ET AL.
	<b>Examiner</b>  Kim, Kiho	<b>Art Unit</b>  2809

<b>SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
250	363.030	9/4/2007	Kiho Kim

<b>SEARCH NOTES</b>		
<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Please see attached a copy of the EAST search history.	9/5/2007	Kiho Kim
Primary Examiner, Constantine Hannaher, was consulted with subject matter.	9/4/2007	Kiho Kim

<b>INTERFERENCE SEARCH</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>